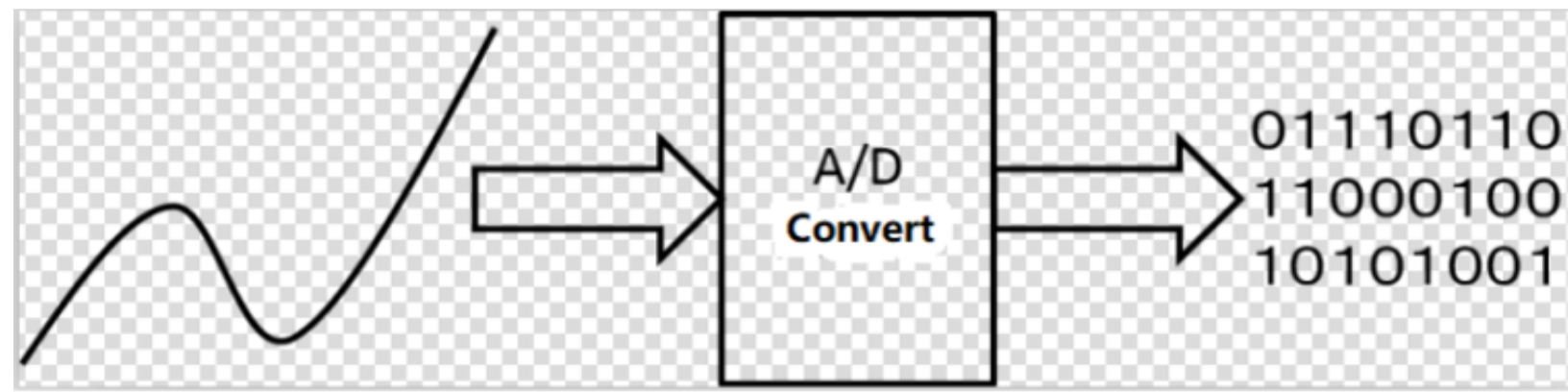




Background

Research Target

Short time, high quality testing of high resolution, low speed analog-to-digital converter (ADC)



For IoT applications

Background

Internet of Things (IoT)

Everything is connected to internet.

- Exchange information
- Process, analyze data on the server.

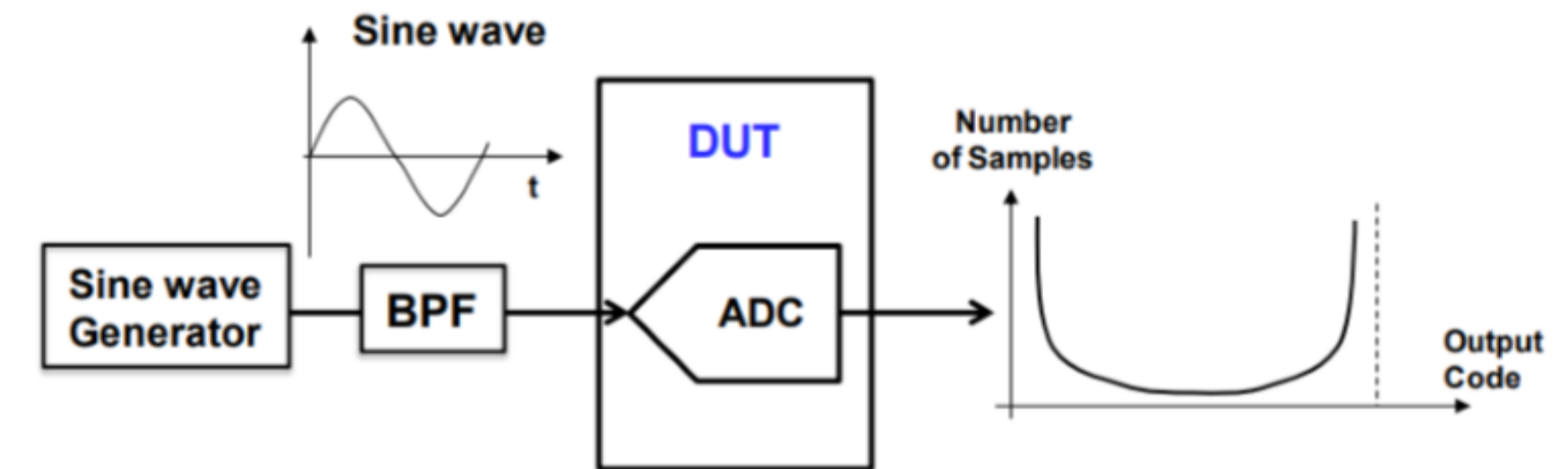


Sensor interface ADC is a key.

ADC Histogram Test

ADC test with high precision linearity

But it takes long time



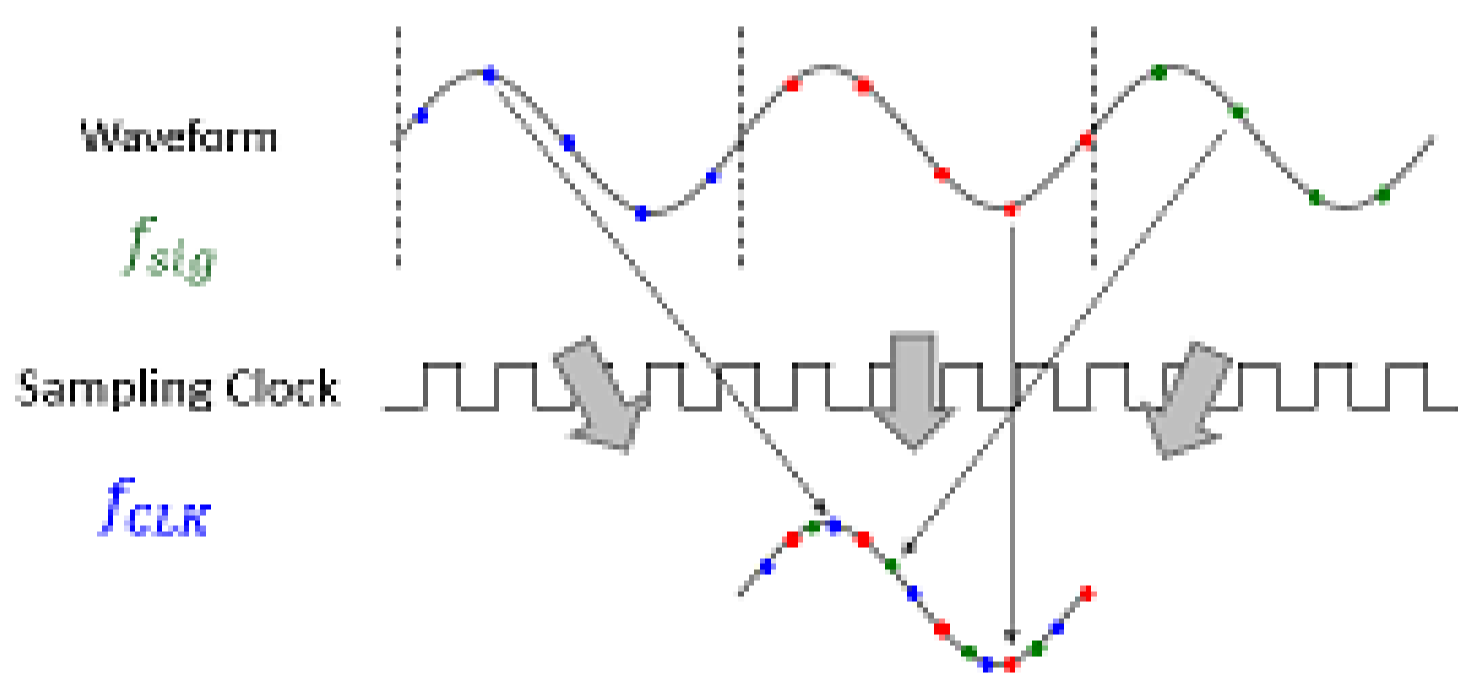
Overview

Sinewave Sampling

Our Approach

Concentration in Specific Codes

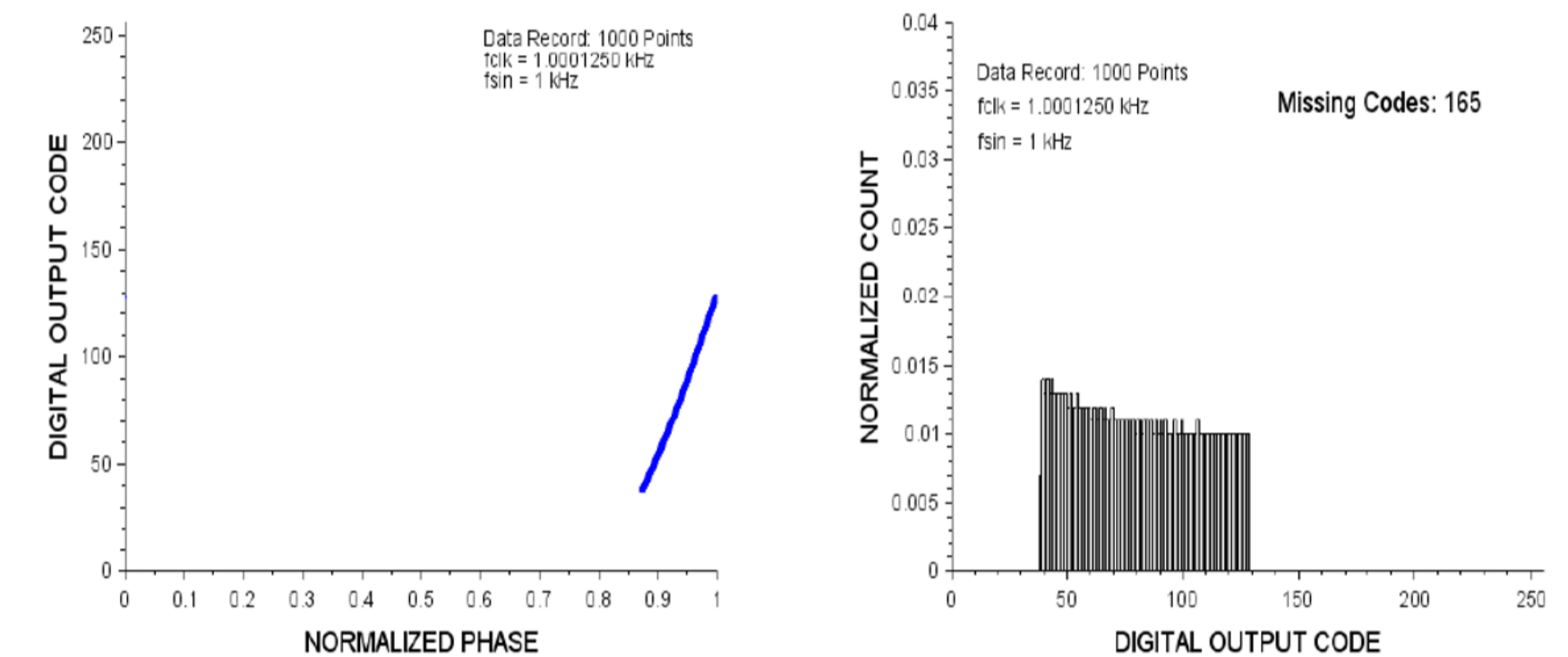
$$x(t) = \sin(2\pi f_{sig}t + \theta)$$



Shorten ADC test time by sampling only necessary range of codes.



Realize by setting proper relationship among f_{CLK} , f_{sig} and θ (initial phase)



Result

Simulation Setting (1)

Simulation Result (1)

$$f_{CLK} = f_{sig} \times \frac{x+1}{x}$$



$$f_{sig} = 1000\text{Hz}$$

$$f_{CLK} = f_{sig} \times \frac{100000 + 1}{100000} = 1.00001f_{sig}$$

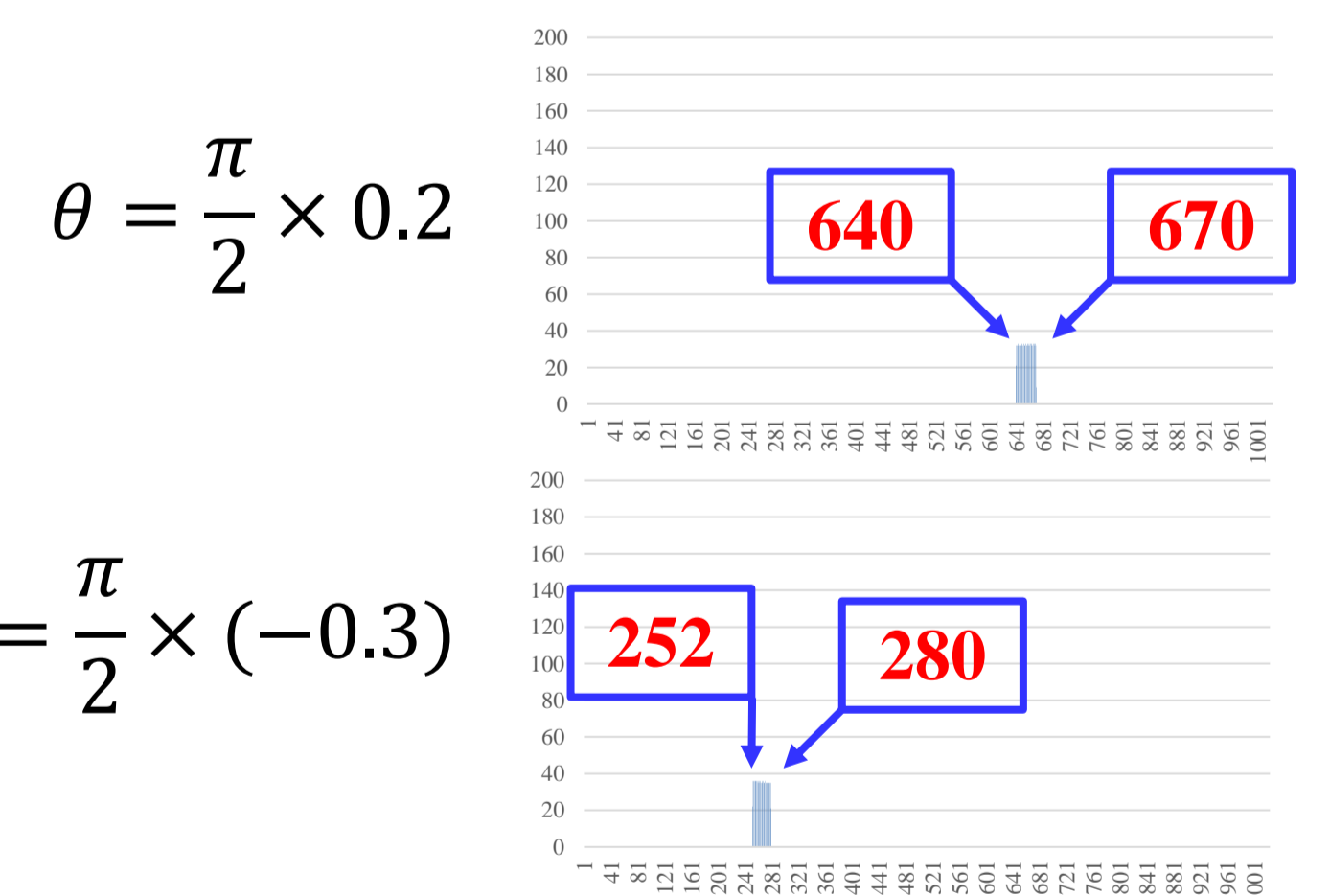
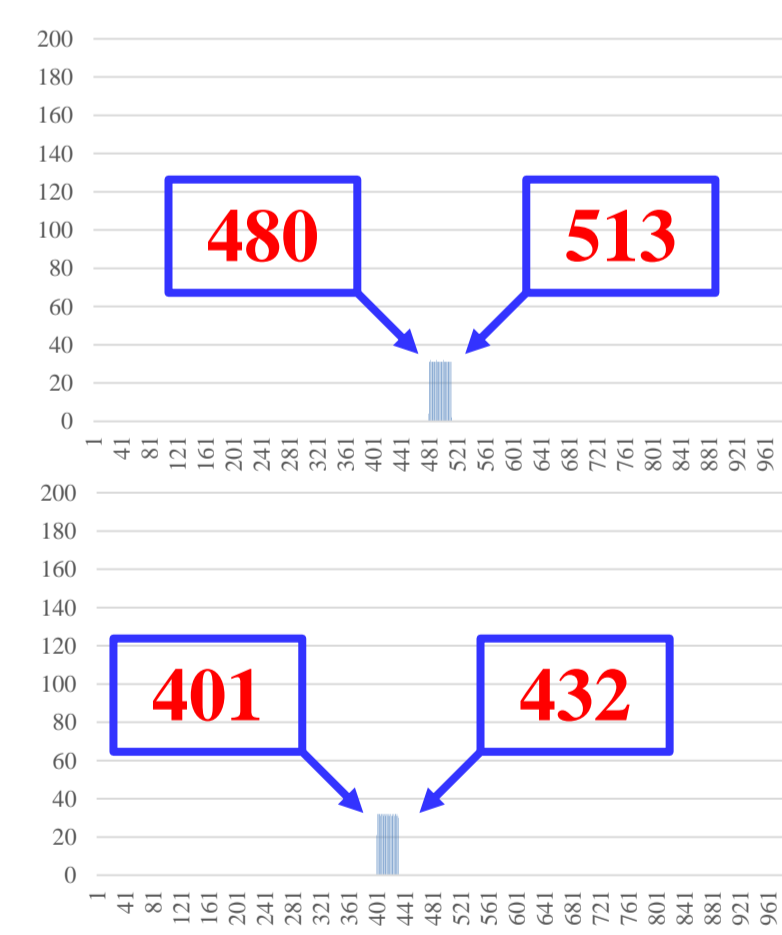
Relationship between f_{CLK} and f_{sig} changes scope of bin.

$$\theta = 0$$

$$\theta = \frac{\pi}{2} \times (-0.1)$$

$$\theta = \frac{\pi}{2} \times 0.2$$

$$\theta = \frac{\pi}{2} \times (-0.3)$$



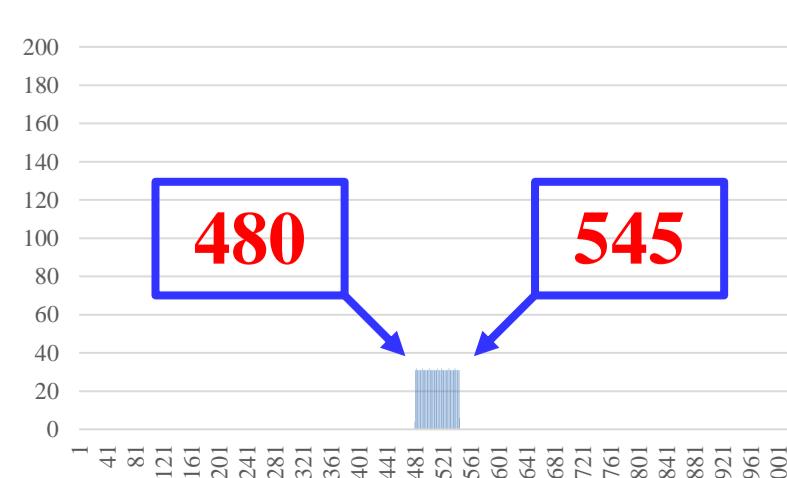
θ changes position of bin.

Simulation Setting (2)

Simulation Result (2)

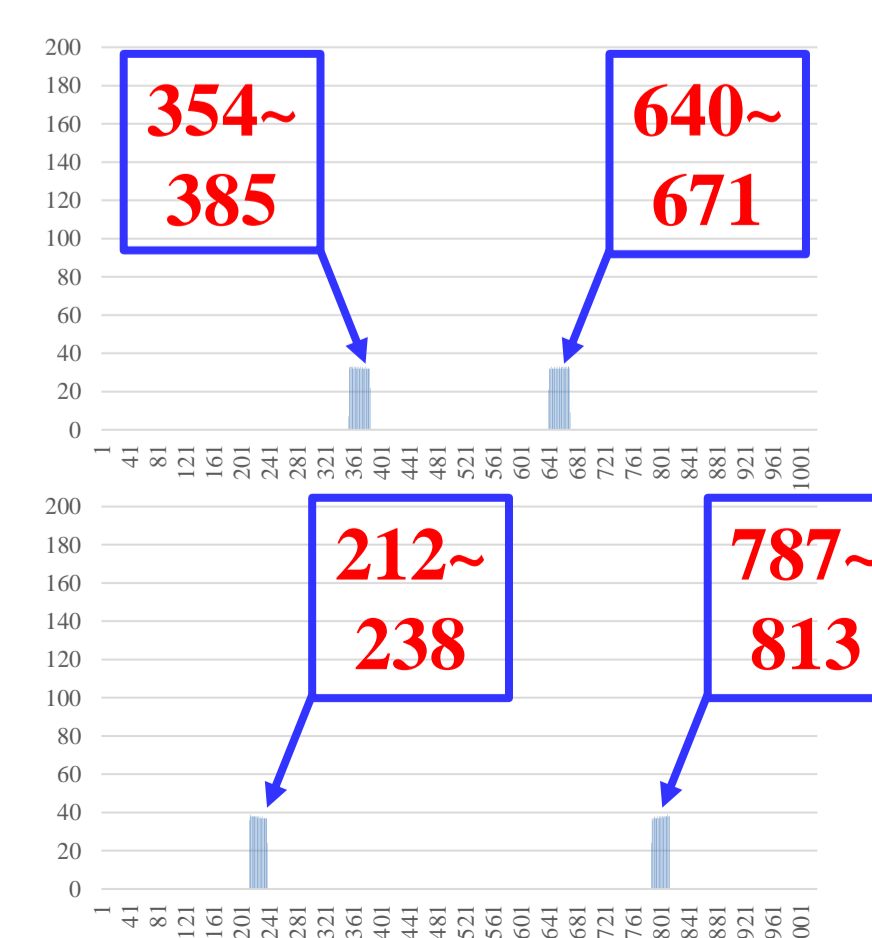
$$f_{CLK} = f_{sig} \times \frac{2(100000 + 1)}{100000} = 2.00002f_{sig}$$

$$\theta = 0$$



$$\theta = \frac{\pi}{2} \times 0.2$$

$$\theta = \frac{\pi}{2} \times 0.4$$



Summary

We investigate relationship among f_{CLK} , f_{sig} and θ (initial phase of waveform) in order to sample only necessary range of codes.

Future work:

- Formulation of relationship among f_{CLK} , f_{sig} and θ
- Quantitatively evaluation of test time reduction.